

STL9524

**In the Abstract:**

Please amend the abstract as follows:

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**COMPREHENSIVE APPLICATION POWER TESTER****Abstract of the Disclosure**

a1 An electronic device power testing method is provided in which applying a nominal voltage to an electronic component, introducing a voltage disruption to the nominal voltage, and repeating the voltage disruption for a specified number of instances is done. The present invention also can be implemented as an electronic device power tester.

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